


<b>Search Notes</b> 	<b>Application/Control No.</b> 10607780	<b>Applicant(s)/Patent Under Reexamination</b> PRATLEY ET AL.
	<b>Examiner</b> LE NGUYEN	<b>Art Unit</b> 2174

SEARCHED			
Class	Subclass	Date	Examiner
715	751	8/2/2009	lvn

SEARCH NOTES		
Search Notes	Date	Examiner
ACM library; EPO, JPO; USPGPub, USPAT: 715/751,753,758,759; 709/204-207; 705/1-11	8/2/2009	lvn
confirmed allowance w/Ba Huynh	9/28/08	lvn

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
715	751	8/2/2009	lvn

/L. N./  
Examiner, Art Unit 2174